Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/731,832	HAJIMIRI ET AL.	
Examiner	Art Unit	
Khanh V. Nguyen	2817	

SEARCHED					
Class	Subclass	Date	Examiner		
330	277	5/23/2005	NKV		
330	310				
330	311				
330	296				
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INI	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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